Preferred Device

# **Silicon Controlled Rectifiers**

# **Reverse Blocking Thyristors**

Designed primarily for half-wave ac control applications, such as motor controls, heating controls and power supplies; or wherever half-wave silicon gate-controlled, solid-state devices are needed.

#### **Features**

- Glass Passivated Junctions with Center Gate Geometry for Greater Parameter Uniformity and Stability
- Small, Rugged, Thermowatt Construction for Low Thermal Resistance, High Heat Dissipation and Durability
- Blocking Voltage to 800 Volts
- Pb-Free Packages are Available\*



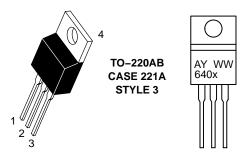
### ON Semiconductor®

http://onsemi.com

# SCRs 16 AMPERES RMS 50 thru 800 VOLTS



#### MARKING DIAGRAM



x = 0, 1, 2, 3, 4 or 5 A = Assembly Location

Y = Year WW = Work Week

PIN ASSIGNMENT		
1	Cathode	
2	Anode	
3	Gate	
4	Anode	

#### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

**Preferred** devices are recommended choices for future use and best overall value.

<sup>\*</sup>For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **MAXIMUM RATINGS**\* $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1)	$V_{DRM,}$		V
$(T_J = -40 \text{ to } 125^{\circ}\text{C}, \text{ Sine Wave } 50 \text{ to } 60 \text{ Hz}; \text{ Gate Open})$	$V_{RRM}$		
2N6400		50	
2N6401		100	
2N6402		200	
2N6403		400	
2N6404		600	
2N6405		800	
On-State Current RMS (180° Conduction Angles; T <sub>C</sub> = 100°C)	I <sub>T(RMS)</sub>	16	Α
Average On-State Current (180° Conduction Angles; T <sub>C</sub> = 100°C)	I <sub>T(AV)</sub>	10	Α
Peak Non-repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, T <sub>J</sub> = 90°C)	I <sub>TSM</sub>	160	Α
Circuit Fusing Considerations (t = 8.3 ms)	l <sup>2</sup> t	145	A <sup>2</sup> s
Forward Peak Gate Power (Pulse Width ≤ 1.0 μs, T <sub>C</sub> = 100°C)	$P_{GM}$	20	W
Forward Average Gate Power (t = 8.3 ms, T <sub>C</sub> = 100°C)	$P_{G(AV)}$	0.5	W
Forward Peak Gate Current (Pulse Width ≤ 1.0 μs, T <sub>C</sub> = 100°C)	I <sub>GM</sub>	2.0	Α
Operating Junction Temperature Range	TJ	-40 to +125	°C
Storage Temperature Range	T <sub>stg</sub>	-40 to +150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

#### THERMAL CHARACTERISTICS

Characteristic		Max	Unit
Thermal Resistance, Junction-to-Case		1.5	°C/W
Maximum Lead Temperature for Soldering Purposes 1/8 in from Case for 10 Seconds	TL	260	°C

Critical Rate-of-Rise of Off-State Voltage ( $V_D$  = Rated  $V_{DRM}$ , Exponential Waveform)

Characteristic		Min	Тур	Max	Unit
OFF CHARACTERISTICS				•	
* Peak Repetitive Forward or Reverse Blocking Current $(V_{AK} = Rated \ V_{DRM} \ or \ V_{RRM}, \ Gate \ Open)$ $T_J = 25^{\circ}C$ $T_J = 125^{\circ}C$	I <sub>DRM</sub> , I <sub>RRM</sub>	_ _	<u>-</u> -	10 2.0	μA mA
ON CHARACTERISTICS			T.		
*Peak Forward On–State Voltage (I <sub>TM</sub> = 32 A Peak, Pulse Width ≤ 1 ms, Duty Cycle ≤ 2%)	$V_{TM}$	-	_	1.7	V
* Gate Trigger Current (Continuous dc) $T_C = 25^{\circ}C$ $(V_D = 12 \text{ Vdc}, R_L = 100 \Omega)$ $T_C = -40^{\circ}C$	I <sub>GT</sub>	-	9.0	30 60	mA
*Gate Trigger Voltage (Continuous dc) $ (V_D = 12 \text{ Vdc}, R_L = 100 \ \Omega) \\ T_C = 25^{\circ}\text{C} \\ T_C = -40^{\circ}\text{C} $	V <sub>GT</sub>	_ _	0.7	1.5 2.5	V
Gate Non–Trigger Voltage ( $V_D$ = 12 Vdc, $R_L$ = 100 $\Omega$ ), $T_C$ = +125°C		0.2	-	-	V
*Holding Current $T_C = 25^{\circ}C$ ( $V_D = 12$ Vdc, Initiating Current = 200 mA, Gate Open) * $T_C = -40^{\circ}C$		-	18 -	40 60	mA
Turn-On Time ( $I_{TM} = 16 \text{ A}$ , $I_{GT} = 40 \text{ mAdc}$ , $V_D = \text{Rated } V_{DRM}$ )		_	1.0	-	μS
Turn-Off Time ( $I_{TM}$ = 16 A, $I_R$ = 16 A, $V_D$ = Rated $V_{DRM}$ ) $T_C = 25^{\circ}C$ $T_1 = +125^{\circ}C$		- -	15 35	- -	μs

<sup>\*</sup>Indicates JEDEC Registered Data.

 $T_J = +125$ °C

50

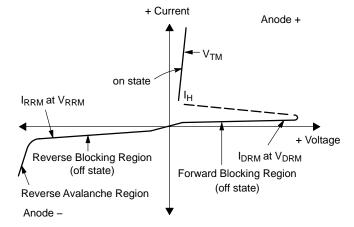
V/μs

dv/dt

V<sub>DRM</sub> and V<sub>RRM</sub> for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

### **Voltage Current Characteristic of SCR**

Symbol	Parameter
V <sub>DRM</sub>	Peak Repetitive Off State Forward Voltage
I <sub>DRM</sub>	Peak Forward Blocking Current
V <sub>RRM</sub>	Peak Repetitive Off State Reverse Voltage
I <sub>RRM</sub>	Peak Reverse Blocking Current
V <sub>TM</sub>	Peak On State Voltage
lu	Holding Current



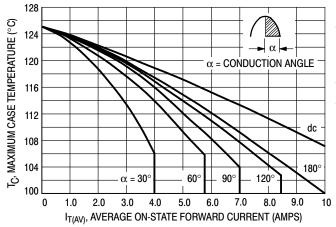


Figure 1. Average Current Derating

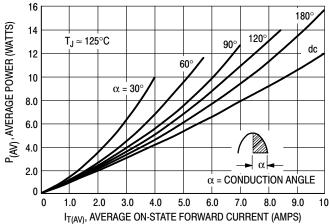


Figure 2. Maximum On-State Power Dissipation

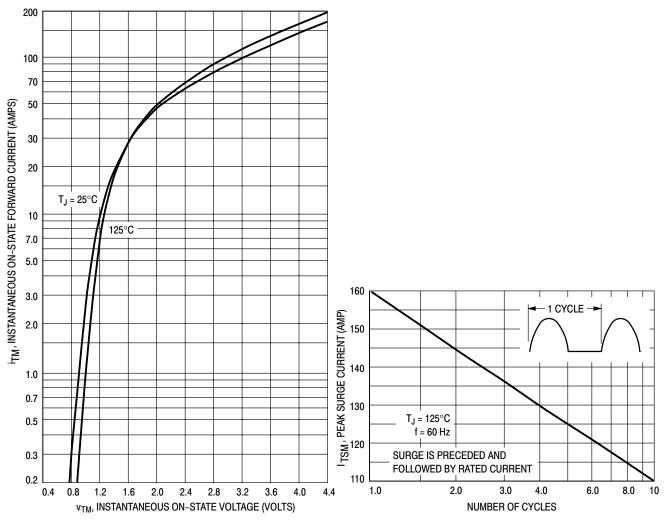


Figure 3. On-State Characteristics

Figure 4. Maximum Non-Repetitive Surge Current

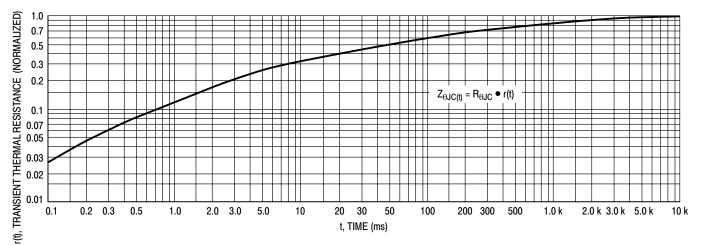


Figure 5. Thermal Response

#### TYPICAL CHARACTERISTICS

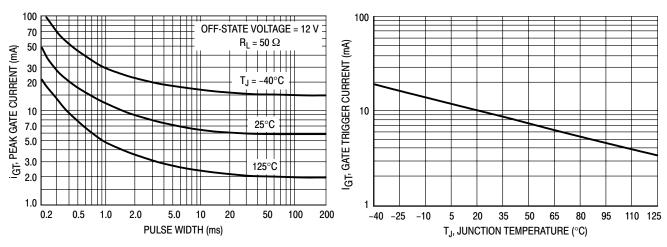


Figure 6. Typical Gate Trigger Current versus Pulse Width

Figure 7. Typical Gate Trigger Current versus Junction Temperature

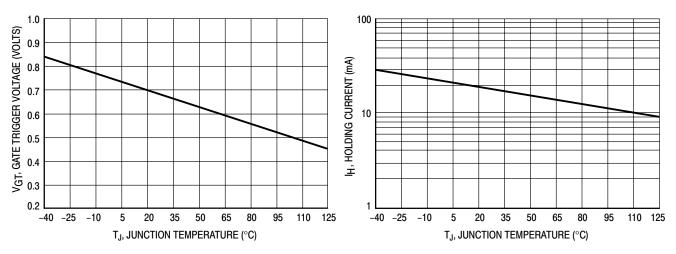


Figure 8. Typical Gate Trigger Voltage versus Junction Temperature

Figure 9. Typical Holding Current versus Junction Temperature

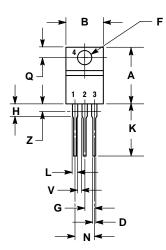
#### **ORDERING INFORMATION**

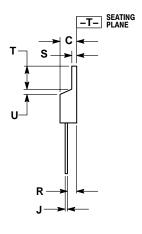
Device	Package	Shipping <sup>†</sup>
2N6400	TO-220AB	
2N6401	TO-220AB	
2N6401G	TO-220AB (Pb-Free)	
2N6402	TO-220AB	500 Units / Box
2N6403	TO-220AB	500 Offits / Box
2N6404	TO-220AB	
2N6405	TO-220AB	
2N6405G	TO-220AB (Pb-Free)	

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

TO-220AB CASE 221A-09 **ISSUE AA** 





#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
С	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.147	3.61	3.73
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
J	0.018	0.025	0.46	0.64
K	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
N	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
T	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
٧	0.045		1.15	
Z		0.080		2.04

#### STYLE 3:

PIN 1. CATHODE

- ANODE 2.
- GATE
- ANODE

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